



## Reliability Data Report Product Family R377

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LT1671 / LT1711 / LT1712 / LT1713 /  
LT1714 / LT1715 / LT1719 / LT1720 /  
LT1721 / LT1868

# Reliability Data Report

## Report Number: R377

Report generated on: Fri Jul 25 08:13:31 PDT 2014

### OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) <sup>1</sup>	No. of FAILURES <sub>2,3</sub>
SIDEBRAZE	77	9813	9813	38	0
SSOP/TSSOP	115	0014	0027	115	0
SOIC/MSOP	900	9813	0131	839	0
Totals	1,092	-	-	992	0

### PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	50	0347	0347	16	0
SSOP/TSSOP	250	9949	1040	54	0
SOIC/MSOP	2048	9810	1306	320	0
SOT	498	0126	1246	22	0
Totals	2,846	-	-	412	0

### TEMP CYCLE FROM -65 TO 150 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	50	0347	0347	50	0
SSOP/TSSOP	240	9949	1040	167	0
SOIC/MSOP	2896	9810	1306	837	0
SOT	550	0126	1246	55	0
Totals	3,736	-	-	1,109	0

### THERMAL SHOCK FROM -65 TO 150 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	174	9949	1040	88	0
SOIC/MSOP	1549	9810	1306	489	0
SOT	548	0126	1246	54	0
Totals	2,271	-	-	631	0

### HIGH TEMPERATURE BAKE AT 175 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SOIC/MSOP	50	0842	0842	25	0
Totals	50	-	-	25	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =1.85 FITS

(3) Mean Time Between Failure in Years = 61772.93

Note: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning